

Notice of References Cited	Application/Control No. 10/570,668		Applicant(s)/Patent Under Reexamination ENDO ET AL.	
	Examiner Bradley K. Smith		Art Unit 2894	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	W.R. RUNYAN and T.J. Schaffner, "Semiconductor Measurements and Instrumentation", New York: McGraw-Hill, 2nd edition, 1998, pp 99-100.			
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	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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